

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

SJ/T 11628-2016

**Solar cell line characterization test method with die size and
electrical**

太阳能电池用硅片尺寸及电学表征在线测试方法
(English Translation)

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What this standard covers

This standard specifies the non-contact on-line test method for the size and electrical characterization of silicon wafers for solar cells (hereinafter referred to as silicon wafers), including dimensions of wafer side length, diagonal length, adjacent side perpendicularity, thickness and total thickness. Electrical characterization includes conductivity type, carrier recombination lifetime, and resistivity. The main contents include normative references, terms and definitions, method summary, interference factors, equipment, sample requirements, test environment, test procedures, precision and test reports.

Document data

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